



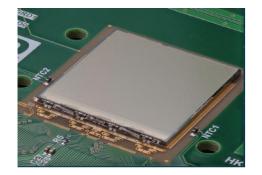
# A reusable verification, emulation and validation flow for ASIC design

**Tomasz Hemperek** 

dectris.com

# **Typical setup**

... in my sensor design experience



ASIC



PC

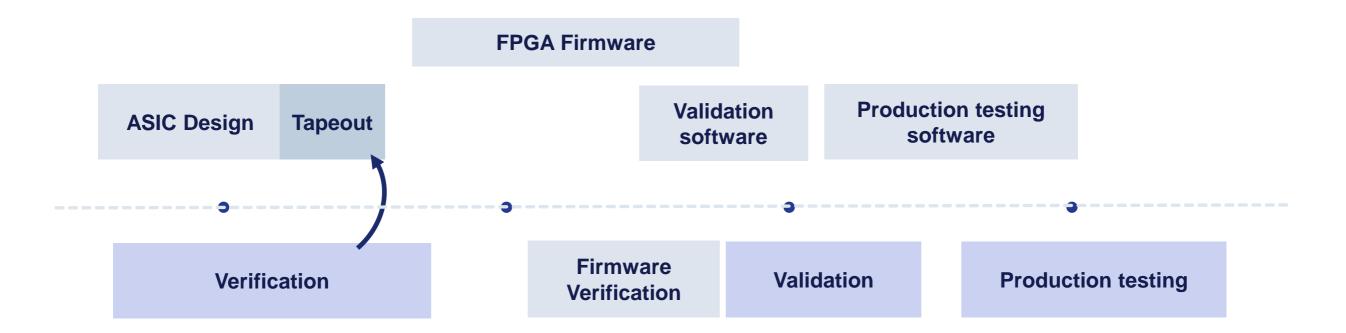






ORConf 2023

# **Development life cycle**

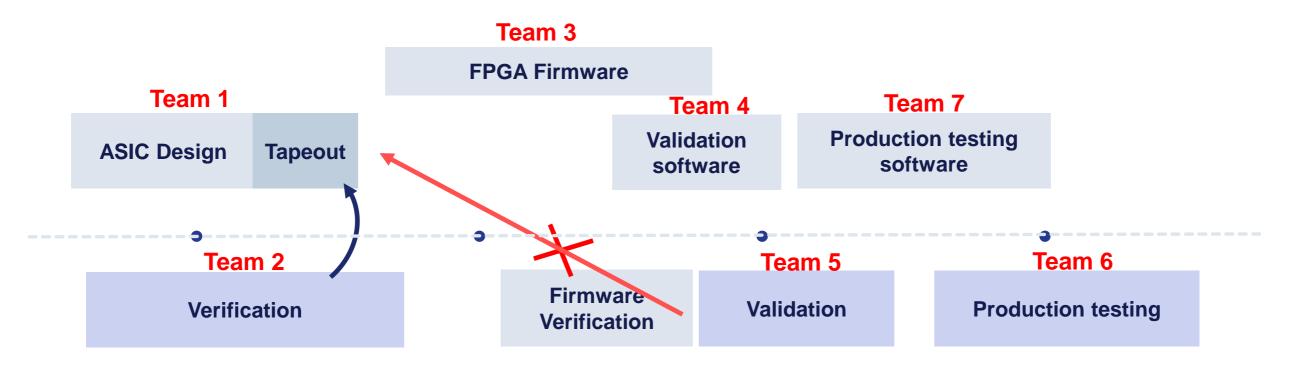


Multiple teams  $\rightarrow$  communication via specifications  $\rightarrow$  non overlapping codebase

**Different timelines**  $\rightarrow$  very costly late discovered specification issues and bugs

### DECTRIS

# **Development life cycle**

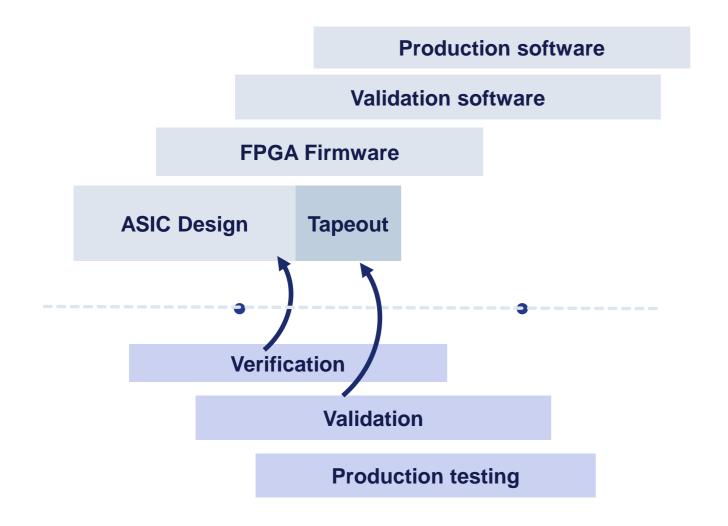


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### DECTRIS

# **Development life cycle**

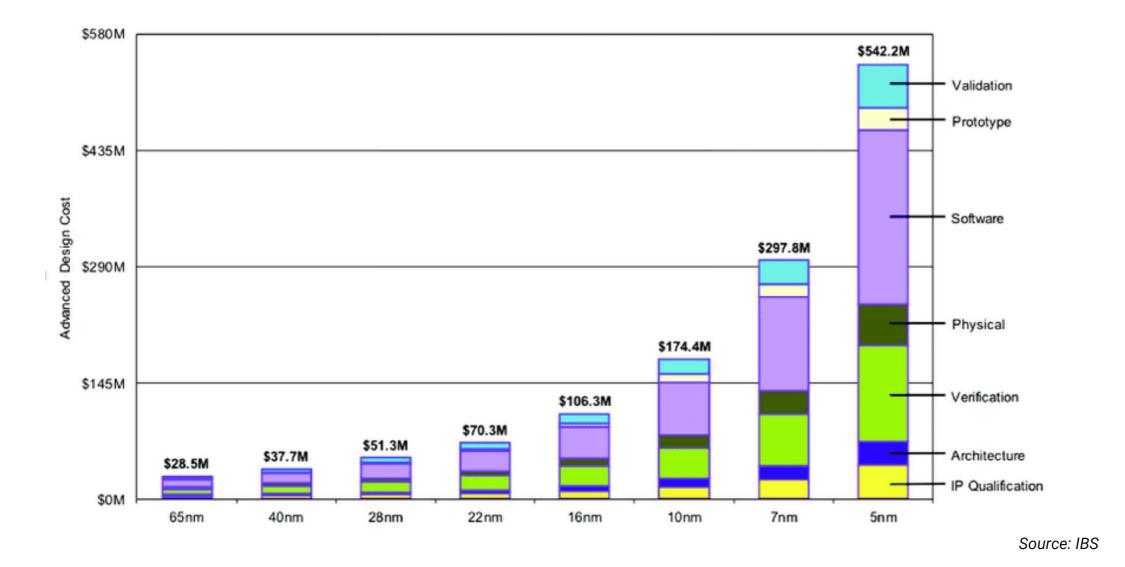


- $\rightarrow$  shorten development time
- $\rightarrow$  improve communication
- $\rightarrow$  early influence on ASIC functionality
- $\rightarrow$  better coverage

Verification is software.

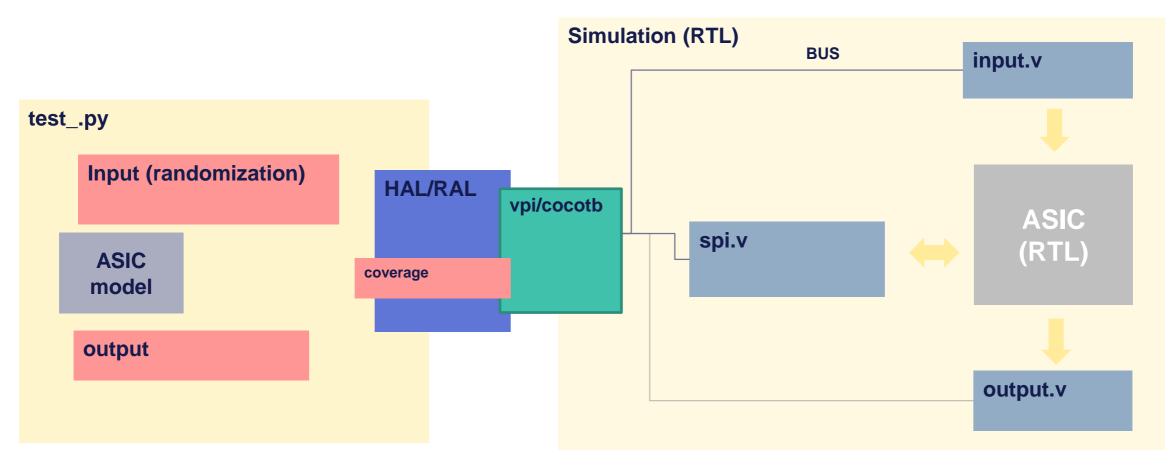


### **Chip Design and Manufacturing Cost**





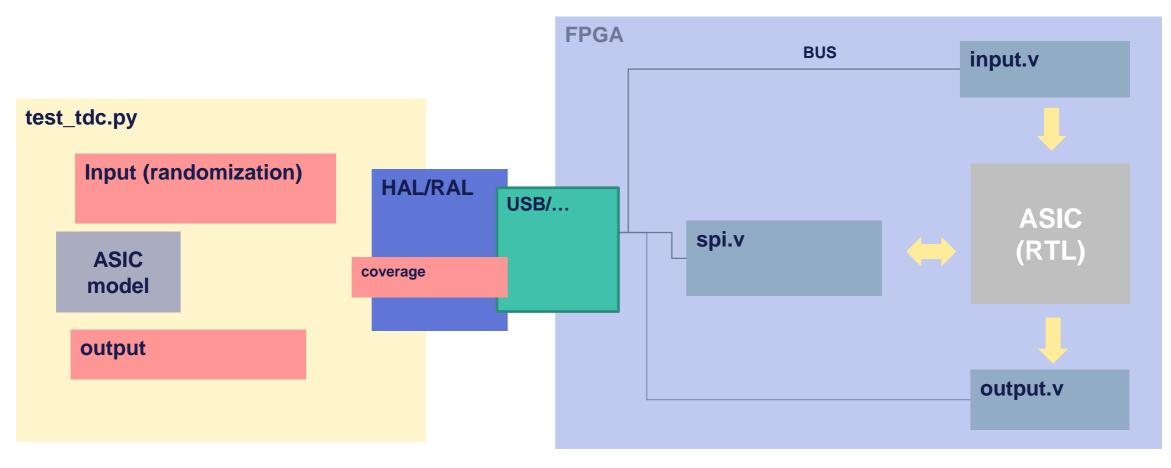
# Simulation/Verification



Move the verification part to the software.

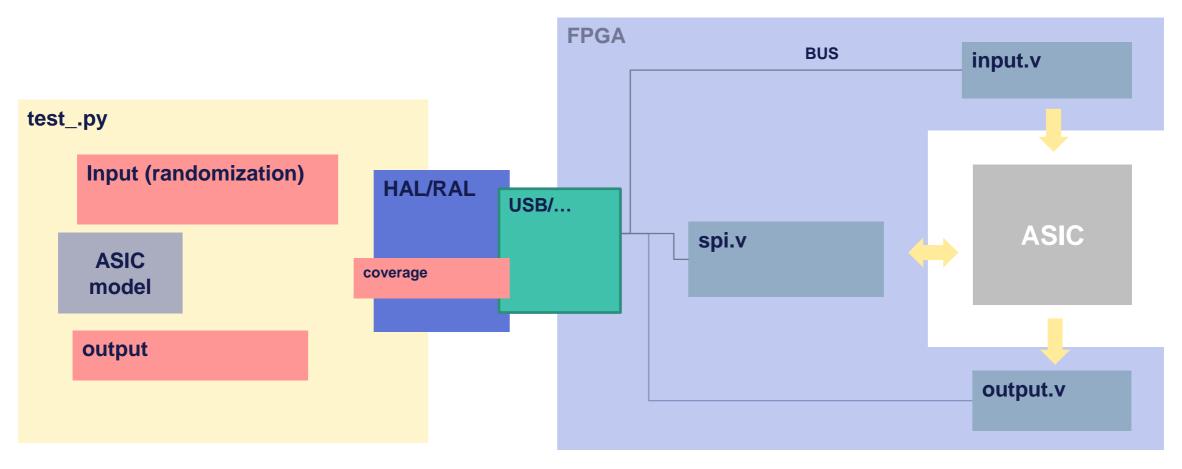


# **Emulation**





# Validation





### **Example use case**

https://github.com/themperek/ORConf23

Disclaimer:

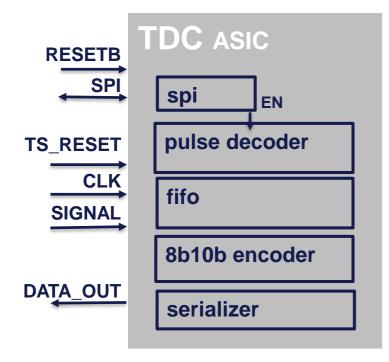
This is a very simple demo.

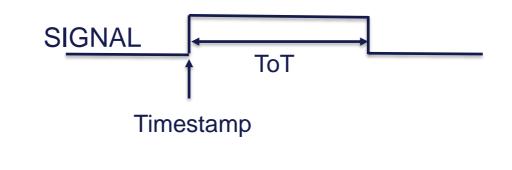
In large part, this work was done while at the University of Bonn (<u>https://gitlab.cern.ch/silab/tdc\_example/</u>). Some amount of "hackery" is required.



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# **TDC / DUT**

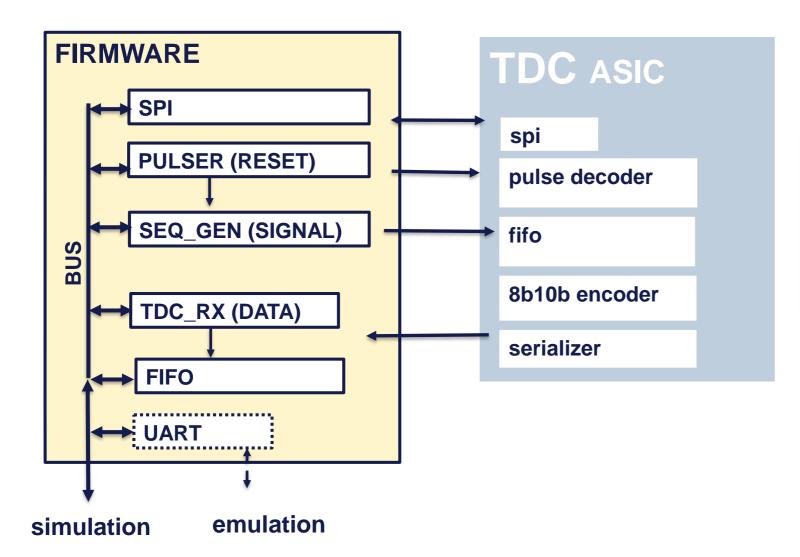




- Single channel TDC
- Configured/Enabled by SPI interface
- Input "SIGNAL" sampled with CLK
- Timestamp (16bit) and ToT (8bit) stored to FIFO
- Timestamp reset with "TS\_RESET"
- Data are 8b10b encoded (simple protocol) and serialized



# **Firmware**



Firmware/software modules based on Basil <a href="https://github.com/silab-bonn/basil">https://github.com/silab-bonn/basil</a>

In emulation use UART https://github.com/ultraembedded/core\_dbg\_bridge



# **Example module**

### tdc\_fw\_core.sv:

```
spi sbus #(
    .BASEADDR (SPI BASEADDR),
    .HIGHADDR (SPI HIGHADDR),
    .ABUSWIDTH(32),
    .MEM BYTES(16)
 spi (
    .BUS_CLK(BUS_CLK),
    .BUS_RST(BUS_RST),
    .BUS ADD(BUS ADD),
    .BUS_DATA_IN(BUS_DATA_IN[7:0]),
    .BUS DATA OUT(SPI DATA OUT),
    .BUS RD(BUS RD),
    .BUS_WR(BUS_WR),
    .SPI CLK (SPI CLK),
    .EXT_START(1'b0),
    .SCLK(SCLK),
    .SDI (SDI),
    .SDO (SDO),
    .SEN (),
    .SLD (SLD)
);
```

### Hardware Abstraction Layer (HAL)

Every firmware (Verilog) module has a corresponding driver

### basil/HL/spi.py:

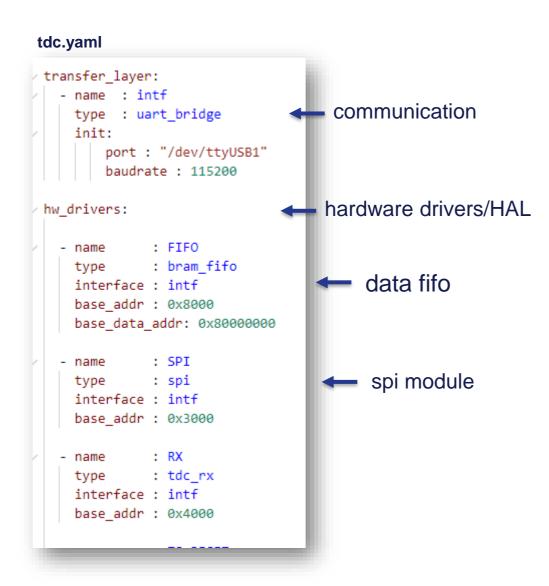
....

```
class spi(RegisterHardwareLayer):
```

```
'''Implement serial programming interface (SPI) driver.
```



# **Top configuration**



Communication interfaces are separate. Memory address mapping are defined.



# **Register Abstraction (RAL)**

# tdc.yaml registers: - name : CONFIG\_REG type : StdRegister driver : None size : 8 fields: - name : EN size : 1 offset : 0

Can define arbitrary size registers An arbitrary amount of fields Can specify bit order Can specify arrays (repeating fields) Can be initialized (also with configuration file)



### **User experience**

### Initialize:

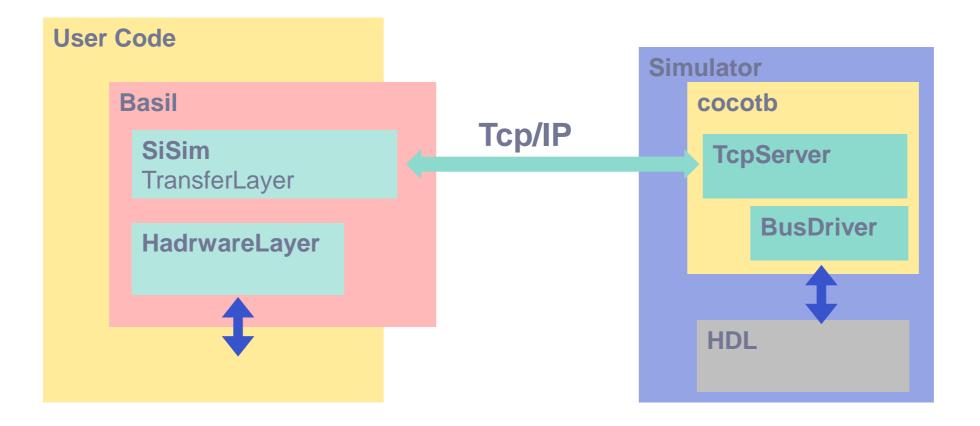
from basil.dut import Dut
self.chip = Dut("tdc.yaml")
self.chip.init()

Same code for verification and validation.

```
def test readout(self):
   self.assertEqual(self.chip["RX"].READY, 1)
   self.chip["CONFIG REG"]["EN"] = 1
                                                       Set configuration and send via SPI
   self.write_config()
                                                       Check 8b10b sync
   self.assertEqual(self.chip["RX"].READY, 1)
                                                       Enable data receiving
   self.chip["RX"].ENABLE RX = 1
   self.chip["TS_RESET"].DELAY = 1
                                                        Timestamp reset
   self.chip["TS RESET"].WIDTH = 1
   self.chip["SIGNAL_SEQ"].set_data([0x00,0x07,0x00,0
   self.chip["SIGNAL SEQ"].REPEAT = 1
                                                        Configure SIGNAL pattern
   self.chip["SIGNAL_SEQ"].SIZE = 8 * 8 + 8 * 16
   self.chip["SIGNAL_SEQ"].EN_EXT_START = 1
   self.chip["FIF0"].RESET
   self.chip["TS_RESET"].START
   while not self.chip["SIGNAL_SEQ"].READY:
                                                       Wait for sequence to finish
       pass
                                                        Check FIFO fill level
   self.assertEqual(self.chip["FIF0"].FIF0_SIZE, 16)
                                                        Get data from FIFO
   data = self.chip["FIF0"].get data()
```



### How simulation works



UART interface is replaced with the simulation interface.



# **Continuous integration**

https://github.com/themperek/ORConf23/actions

Triggered via push 9 minutes ago	526 master	Status Success	Total duration 8m 46s	Artifacts <b>4</b>	
ci.yml build firm	iware (	(F4PGA)	tes	t on FPC	GA (self-hosted)
<ul> <li>build-fw</li> </ul>	6m 21s	• 🛛 emulation	2m 1(	)s	
simulation	3m 34s				
Artifacts Produced during runtime					
Name				Size	
💮 bitfile				2.09 MB	
build-reports				8.1 MB	reports
emulation-reports				35.9 KB	
simulation-reports				1.59 KB	





### **Test reports**

### tomasz.hemperek> pytest -v test

<pre>test/test_tdc.py::TestTDC::test_parameterized_0 PASSED</pre>	[ 16%]
<pre>test/test_tdc.py::TestTDC::test_parameterized_1 PASSED</pre>	[ 33%]
<pre>test/test_tdc.py::TestTDC::test_parameterized_2 PASSED</pre>	[ 50%]
<pre>test/test_tdc.py::TestTDC::test_parameterized_3 PASSED</pre>	[ 66%]
<pre>test/test_tdc.py::TestTDC::test_simple_readout PASSED</pre>	[ 83%]
<pre>test/test_tdc.py::TestTDC::test_spi PASSED</pre>	[100%]

------ 6 passed in 10.00s -----

### report.html

### Report generated on 12-Sep-2023 at 14:11:19 by pytest-html v4.0.1

### Environment

Python	3.8.15
Platform	Linux-4.18.0-477.13.1.el8_8.x86_64-x86_64-with-glibc2.17
Packages	<ul><li> pytest: 7.4.0</li><li> pluggy: 1.3.0</li></ul>
Plugins	<ul> <li>cocotb-test: 0.2.3</li> <li>metadata: 3.0.0</li> <li>html: 4.0.1</li> <li>xdist: 3.3.1</li> </ul>

### Summary

### 6 tests took 00:00:09.

(Un)check the boxes to filter the results.

🔽 0 Failed, 🔽 6 Passed, 🔽 0 Skipped, 🔽 0 Expected failures, 💟 0 Unexpected passes, 💟 0 Errors, 💟 0 Reruns 👘 Show all details 🖉 Hide all detail				
Result 🔺	Test	Duration	Links	
Passed	test/test_tdc.py::TestTDC::test_parameterized_0	00:00:02		
Passed	test/test_tdc.py::TestTDC::test_parameterized_1	00:00:02		
Passed	test/test_tdc.py::TestTDC::test_parameterized_2	00:00:02		
Passed	test/test_tdc.py::TestTDC::test_parameterized_3 00:00:02			
Passed	test/test_tdc.py::TestTDC::test_simple_readout	00:00:02		
Passed	test/test_tdc.py::TestTDC::test_spi	00:00:01		



# **Coverage and Randomization**

### Define covergroup:

@vsc.covergroup class cov(object): def \_\_init\_\_(self): self.with\_sample(dict(data=vsc.bit\_t(8))) self.data\_cp = vsc.coverpoint(self.data, bins=dict(data=vsc.bin\_array([8], [0, 255])))

### Sample:

```
@parameterized.expand([[x] for x in range(4)])
def test_parameterized(self, data):
    self.assertEqual(self.chip["RX"].READY, 1)
```

self.cover.sample(data \* 32)

ret = self.rw\_dut\_spi(0x91)
self.assertEqual(ret, 0x91)

PyUCIS Viewer _							
<u>F</u> ile							
Name	Coverage	Status					
<ul> <li>TYPE: cov</li> </ul>	50.00%	50%					
▼ CVP: data_cp	50.00%	<b>5</b> 0%					
а	0	0					
b	2	2					

PyVSC: <a href="https://github.com/fvutils/pyvsc">https://github.com/fvutils/pyvsc</a>



# **Testing with pytest**

### **Tests parametrization:**

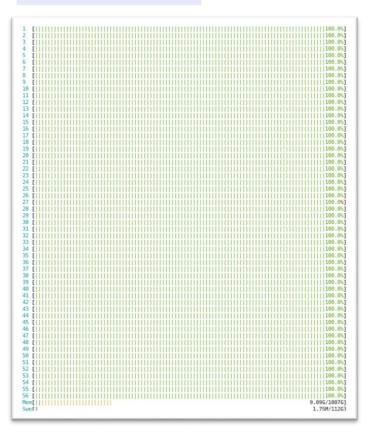
@parameterized.expand([[x] for x in range(4)])
def test\_parameterized(self, data):

self.assertEqual(self.chip["RX"].READY, 1)

### **Parallel execution :**

pip install pytest-xdist

pytest -n auto

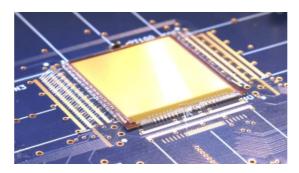




### Conclusions

- Moving teams together for better collaboration
- Verification is software, let firmware/software contribute early
- Reused for validation and production testing
- Understand limitations
- Can be an organizational challenge
- Can be done with all open tools and modern infrastructure
- Successfully used to develop and test ASICs (example: https://doi.org/10.1016/j.nima.2020.164721)

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# Thank you for your attention!

